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**J** lena



Günter-Köhler-Institut für Fügetechnik und Werkstoffprüfung

Understanding and Optimization of ultra-short pulse laser ablation of technical ceramics based on experimental data







Maria Friedrich

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### Laser processing of glass and ceramics



### Outline



### 1. Experimental Approach

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Fundamentals



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June 7, WOST 2019

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### 1. Experimental Approach

#### Multitude of process parameters ...



#### **Process Parameters**

## ... results in various surface qualities



### 1. Experimental Approach

#### **Process Parameters**

#### Multi-dimensional parameter space

 $\rightarrow$  Value ranges are unevenly distributed



- Wavelength:
- 1064 nm, 532 nm, 355 nm
- Pulse duration:
- Repetition rate:
- Max. power:

230 fs – 10 ps

25 W

< 1 MHz

Power P [W]



#### Fluence (Energy density) F [J/cm<sup>2</sup>]



#### Pulse Overlap O<sub>h</sub> [%]



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### 1. Experimental Approach

#### Procedure

#### Multi-dimensional parameter space

- $\rightarrow$  Sensitivity analysis, meta model, optimization
- $\rightarrow$  Identification of main parameters and non-linear effects







#### Input Parameters

#### DoE 1.0

- Use of widest possible parameter range within the process window of one material
- Aim: identification of main parameters

#### INPUTS

• Wavelength:  $\lambda = 355 / 532 / 1064 \text{ nm}^{+}$ 

Ρ

- Focal length: f = 40 / 100 / 250 mm
- Focus diameter:  $d_f = 11 \dots 110 \mu m$
- Number of Designs: 100
- Experimental Design according to native parameters

Power

Line distance a<sub>L</sub>

Pulse distance a<sub>P</sub>

#### DoE 3.0

- Restriction to a few parameters
- Aim: maximum increase of model quality, good comparability of different materials

#### **INPUTS**

- Wavelength:  $\lambda = 532 \text{ nm} = \text{const.}$
- Focal length: f = 100 mm = const.
- Focus diameter:  $d_f = 14 \ \mu m = const.$
- Number of Designs: 50
- Experimental Design according to derived parameters
  - Fluence
  - $\succ$  Vertical pulse overlap  $O_v$
  - Horizontal pulse overlap

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 $d_{f}$ 

 $O_h$ 

#### **Correlation Matrix**

#### DoE 1.0

- Use of widest possible parameter range within the process window of one material
- Aim: identification of main parameters



#### DoE 3.0

- Restriction to a few parameters
- Aim: maximum increase of model quality, good comparability of different materials



→ Avoidance of input correlations

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#### Anthill Plots

#### DoE 1.0

- Use of widest possible parameter range within the process window of one material
- Aim: identification of main parameters



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#### DoE 3.0

- Restriction to a few parameters
- Aim: maximum increase of model quality, good comparability of different materials



#### DoE 1.0

- Use of widest possible parameter range within the process window of one material
- Aim: identification of main parameters



→ Good roughness model due to large value range ( $Ra = 0,4 \dots 3,8 \mu m$ )

#### DoE 3.0

- Restriction to a few parameters
- Aim: maximum increase of model quality, good comparability of different materials





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#### Coefficient of Prognosis

#### DoE 1.0

- Use of widest possible parameter range within the process window of one material
- Aim: identification of main parameters



→ Good roughness model due to large value range ( $Ra = 0,4 \dots 3,8 \mu m$ )

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#### DoE 3.0

- Restriction to a few parameters
- Aim: maximum increase of model quality, good comparability of different materials



#### → Weak roughness model ( $Ra = 0,5 \dots 1,1 \mu m$ ) → Good models for depth-related parameters

### 3. Sensitivity Analysis

#### Ablation rate

- Ablation rate increases with power
- Line distance and pulse distance interact
  - $\rightarrow$  High values: high speed
  - ightarrow Small values: high material removal





*r<sub>min</sub>* ≈ 0 mm³/min

*r<sub>max</sub>* = 7.8 mm³/min



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### 3. Sensitivity Analysis

#### Roughness



- Optimal pulse overlap depends on fluence
- With increasing fluence: minimum shifts to smaller values









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### 3. Sensitivity Analysis

#### Different materials

- Transfer of DoE 3.0 to other materials (LTCC, AIN, Porcelain)
- Use of "Space filling Latin Hypercube Sampling"



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### 4. Industrial Applications

- Microsystems technology: fabrication of precise cavities in Al<sub>2</sub>O<sub>3</sub> / LTCC for the positioning of microchips:
  - $\circ$  ~ Profile depth: 800  $\mu m$
  - Bottom: 5 x 5 mm<sup>2</sup>
  - Flank angle: 30°





• High-value consumer goods: manufacturing of individual design structures in porcelain: Example: "Zugspitze" ( $\Delta X = 25 \text{ mm}$ ,  $\Delta Z = 2,1 \text{ mm}$ )

Stack of 100 layers

Ablation of negative volume

#### 3D freeform profile







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### Summary





- optiSLang can be used to create physically meaningful metamodels based on experimental data
- The further development of the DoE (symmetrical parameter space, restriction to a few parameters) increased the model quality
- For a comprehensive understanding of the process, all models should be considered
  - DoE 1.0: Knowledge about whole parameter space
  - DoE 3.0: Comparison of different materials
- Native and derived parameters must be considered separately, but both provide important insights
  - > Native parameters: depth-related outputs, focus diameter
  - Derived parameters: roughness-related outputs
- General question: What knowledge would you like to achieve?
  - Reduce the experimental design to provide additional insights!

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#### M. Eng. Maria Friedrich

ifw - Günter-Köhler-Institut für Fügetechnik und Werkstoffprüfung GmbH Otto-Schott-Str. 13 07745 Jena

- Phone: +49 (0) 3641 204 190
- E-Mail: mfriedrich@ifw-jena.de

#### www.ifw-jena.de

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